

Power MOSFET

| PRODUCT SUMMARY | | |
|---------------------------|-------------------|------|
| V_{DS} (V) | - 60 | |
| $R_{DS(on)}$ (Ω) | $V_{GS} = - 10$ V | 0.50 |
| Q_g (Max.) (nC) | 12 | |
| Q_{gs} (nC) | 3.8 | |
| Q_{gd} (nC) | 5.1 | |
| Configuration | Single | |

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Advanced Process Technology
- Surface Mount (IRF9Z14S, SiHF9Z14S)
- Low-Profile Through-Hole (IRF9Z14L, SiHF9Z14L)
- 175 °C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Compliant to RoHS Directive 2002/95/EC



RoHS*
COMPLIANT
HALOGEN
FREE
Available

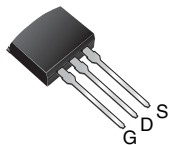
DESCRIPTION

Third generation Power MOSFETs from Vishay utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

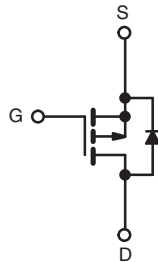
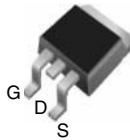
The D²PAK is a surface mount power package capable of accommodating die size up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²PAK is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application.

The through-hole version (IRF9Z14L, SiHF9Z14L) is available for low-profile applications.

I²PAK (TO-262)



D²PAK (TO-263)



P-Channel MOSFET

| ORDERING INFORMATION | | | |
|---------------------------------|-----------------------------|-------------------------------|-----------------------------|
| Package | D ² PAK (TO-263) | D ² PAK (TO-263) | I ² PAK (TO-262) |
| Lead (Pb)-free and Halogen-free | SiHF9Z14S-GE3 | SiHF9Z14STRL-GE3 ^a | SiHF9Z14L-GE3 |
| Lead (Pb)-free | IRF9Z14SPbF | IRF9Z14STRLPbF ^a | IRF9Z14LPbF |
| | SiHF9Z14S-E3 | SiHF9Z14STL-E3 ^a | SiHF9Z14L-E3 |
| SnPb | IRF9Z14S | IRF9Z14STRL ^a | - |
| | SiHF9Z14S | SiHF9Z14STL ^a | - |

Note

a. See device orientation.

| ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted) | | | |
|---|--------------------|------------------|-------|
| PARAMETER | SYMBOL | LIMIT | UNIT |
| Drain-Source Voltage | V_{DS} | - 60 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | |
| Continuous Drain Current ^e | V_{GS} at - 10 V | $T_C = 25$ °C | - 6.7 |
| | | $T_C = 100$ °C | - 4.7 |
| Pulsed Drain Current ^{a, e} | | - 27 | A |
| Linear Derating Factor | | 0.29 | W/°C |
| Single Pulse Avalanche Energy ^{b, e} | E_{AS} | 140 | mJ |
| Avalanche Current ^a | I_{AR} | - 6.7 | A |
| Repetitive Avalanche Energy ^a | E_{AR} | 4.3 | mJ |
| Maximum Power Dissipation | | $T_C = 25$ °C | 43 |
| | | $T_A = 25$ °C | 3.7 |
| Peak Diode Recovery dV/dt ^{c, e} | dV/dt | - 4.5 | V/ns |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | - 55 to + 175 | °C |
| Soldering Recommendations (Peak Temperature) | for 10 s | 300 ^d | |

Notes


- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = - 25$ V, starting $T_J = 25$ °C, $L = 3.6$ mH, $R_{\theta} = 25$ Ω , $I_{AS} = - 6.7$ A (see fig. 12).
- $I_{SD} \leq - 6.7$ A, $dI/dt \leq 90$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 175$ °C.
- 1.6 mm from case.
- Uses IRF9Z14, SiHF9Z14 data and test conditions.

* Pb containing terminations are not RoHS compliant, exemptions may apply

| THERMAL RESISTANCE RATINGS | | | | |
|--|------------|------|------|------|
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient (PCB Mounted, steady-state) ^a | R_{thJA} | - | 40 | °C/W |
| Maximum Junction-to-Case (Drain) | R_{thJC} | - | 3.5 | |

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS ($T_J = 25\text{ °C}$, unless otherwise noted) | | | | | | |
|---|---------------------|--|------|-------|-----------|---------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| Static | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0\text{ V}$, $I_D = -250\text{ }\mu\text{A}$ | -60 | - | - | V |
| V_{DS} Temperature Coefficient | $\Delta V_{DS}/T_J$ | Reference to 25 °C , $I_D = -1\text{ mA}^c$ | - | -0.06 | - | V/°C |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = -250\text{ }\mu\text{A}$ | -2.0 | - | -4.0 | V |
| Gate-Source Leakage | I_{GSS} | $V_{GS} = \pm 20\text{ V}$ | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = -60\text{ V}$, $V_{GS} = 0\text{ V}$ | - | - | -100 | μA |
| | | $V_{DS} = -48\text{ V}$, $V_{GS} = 0\text{ V}$, $T_J = 150\text{ °C}$ | - | - | -500 | |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = -10\text{ V}$, $I_D = -4.0\text{ A}^b$ | - | - | 0.5 | Ω |
| Forward Transconductance | g_{fs} | $V_{DS} = -25\text{ V}$, $I_D = -4.0\text{ A}^c$ | 1.4 | - | - | S |
| Dynamic | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}$, $V_{DS} = -25\text{ V}$, $f = 1.0\text{ MHz}$, see fig. 5 ^c | - | 270 | - | μF |
| Output Capacitance | C_{oss} | | - | 170 | - | |
| Reverse Transfer Capacitance | C_{rss} | | - | 31 | - | |
| Total Gate Charge | Q_g | $V_{GS} = -10\text{ V}$, $I_D = -6.7\text{ A}$, $V_{DS} = -48\text{ V}$, see fig. 6 and 13 ^{b, c} | - | - | 12 | nC |
| Gate-Source Charge | Q_{GS} | | - | - | 3.8 | |
| Gate-Drain Charge | Q_{GD} | | - | - | 5.1 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = -30\text{ V}$, $I_D = -6.7\text{ A}$, $R_g = 24\text{ }\Omega$, $R_D = 4.0\text{ }\Omega$, see fig. 10 ^b | - | 11 | - | ns |
| Rise Time | t_r | | - | 63 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 10 | - | |
| Fall Time | t_f | | - | 31 | - | |
| Internal Source Inductance | L_S | Between lead, and center of die contact | - | 7.5 | - | nH |
| Drain-Source Body Diode Characteristics | | | | | | |
| Continuous Source-Drain Diode Current | I_S | MOSFET symbol showing the integral reverse p - n junction diode  | - | - | -6.7 | A |
| Pulsed Diode Forward Current ^a | I_{SM} | | - | - | -27 | |
| Body Diode Voltage | V_{SD} | $T_J = 25\text{ °C}$, $I_S = -6.7\text{ A}$, $V_{GS} = 0\text{ V}^b$ | - | - | -5.5 | V |
| Drain-Source Body Diode Characteristics | | | | | | |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25\text{ °C}$, $I_F = -6.7\text{ A}$, $dI/dt = 100\text{ A}/\mu\text{s}^b, c$ | - | 80 | 160 | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | - | 96 | 190 | nC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D) | | | | |

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.
- Uses IRF9Z14, SiHF9Z14 data and test conditions.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

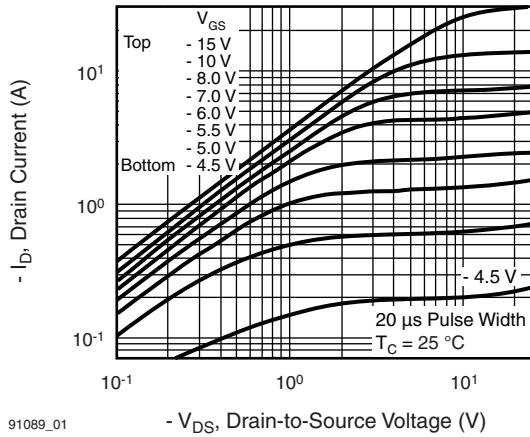


Fig. 1 - Typical Output Characteristics

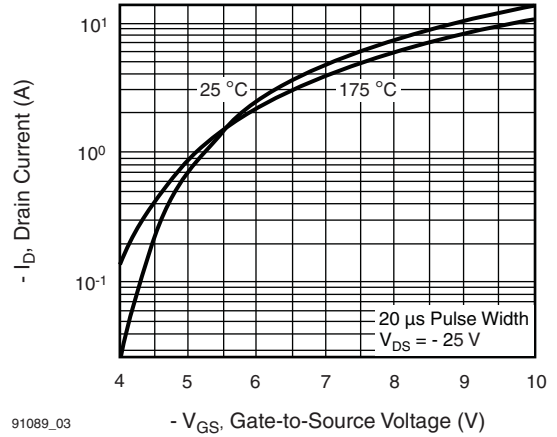


Fig. 3 - Typical Transfer Characteristics

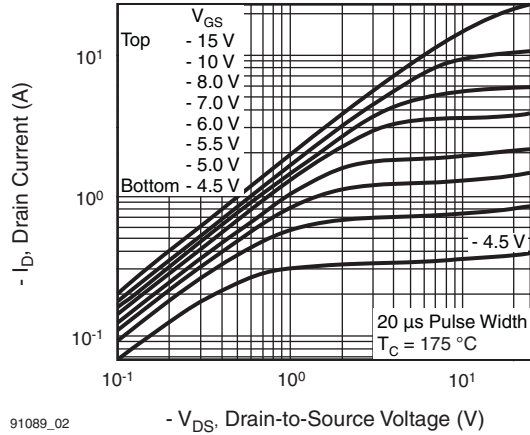


Fig. 2 - Typical Output Characteristics

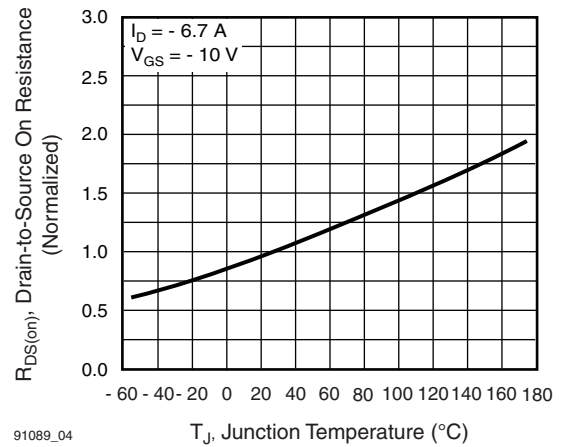


Fig. 4 - Normalized On-Resistance vs. Temperature

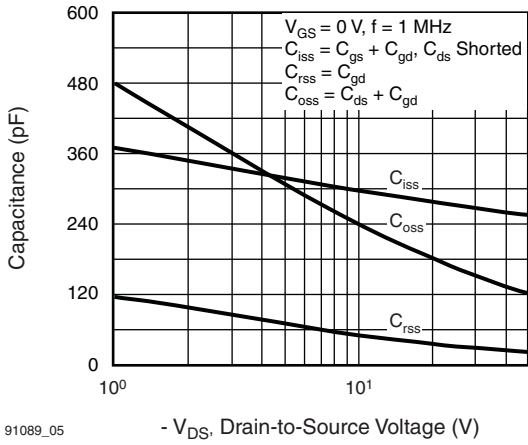


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

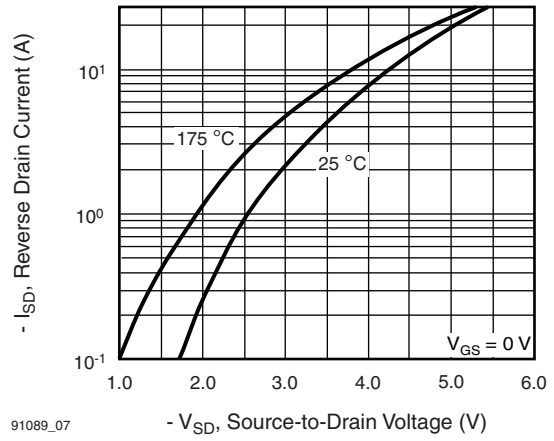


Fig. 7 - Typical Source-Drain Diode Forward Voltage

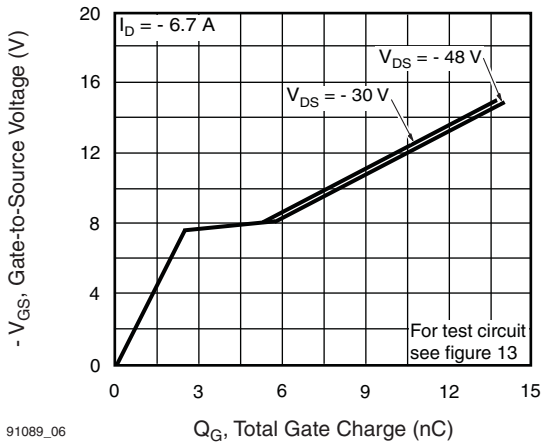


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

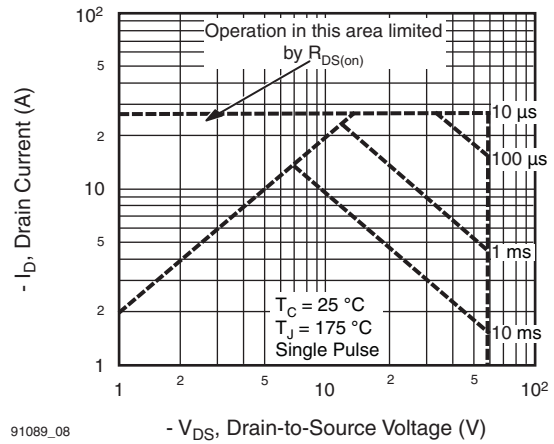
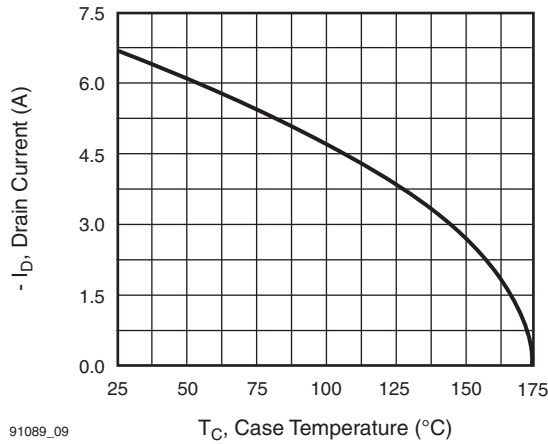


Fig. 8 - Maximum Safe Operating Area



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Fig. 9 - Maximum Drain Current vs. Case Temperature

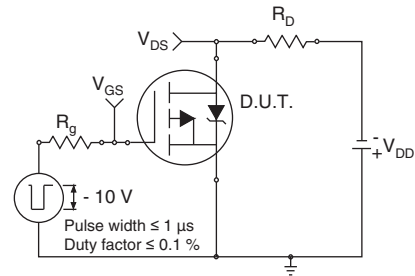


Fig. 10a - Switching Time Test Circuit

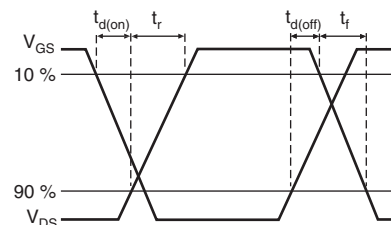
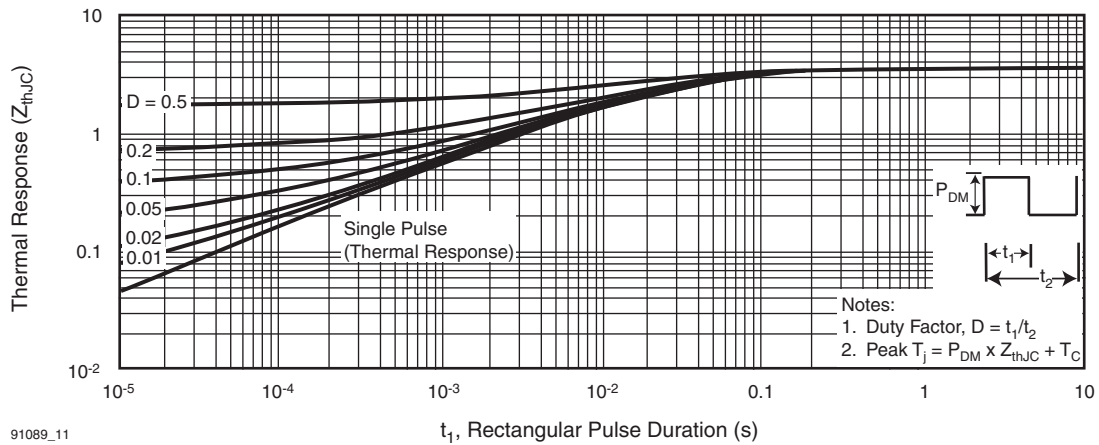


Fig. 10b - Switching Time Waveforms



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Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

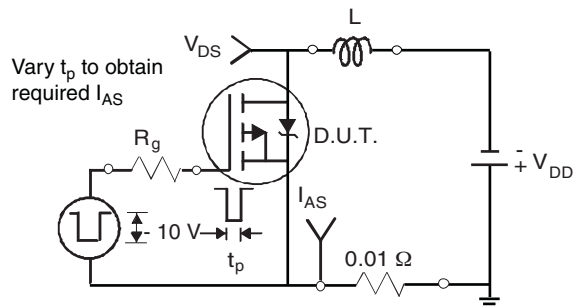


Fig. 12a - Unclamped Inductive Test Circuit

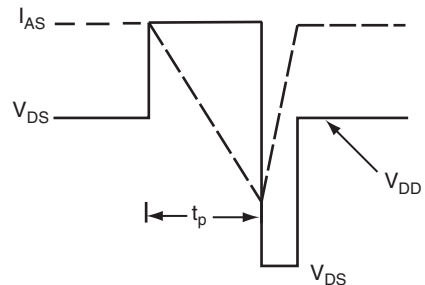


Fig. 12b - Unclamped Inductive Waveforms

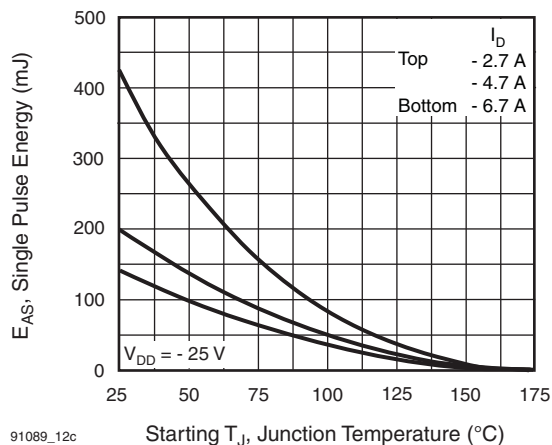


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

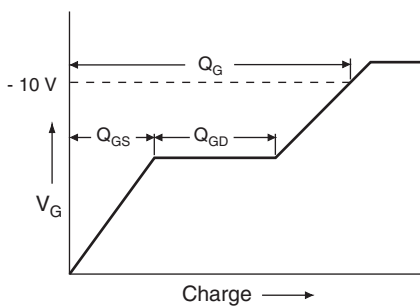


Fig. 13a - Basic Gate Charge Waveform

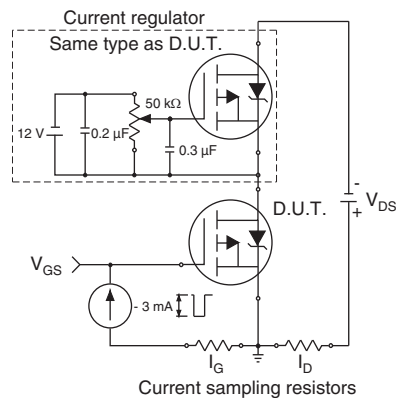
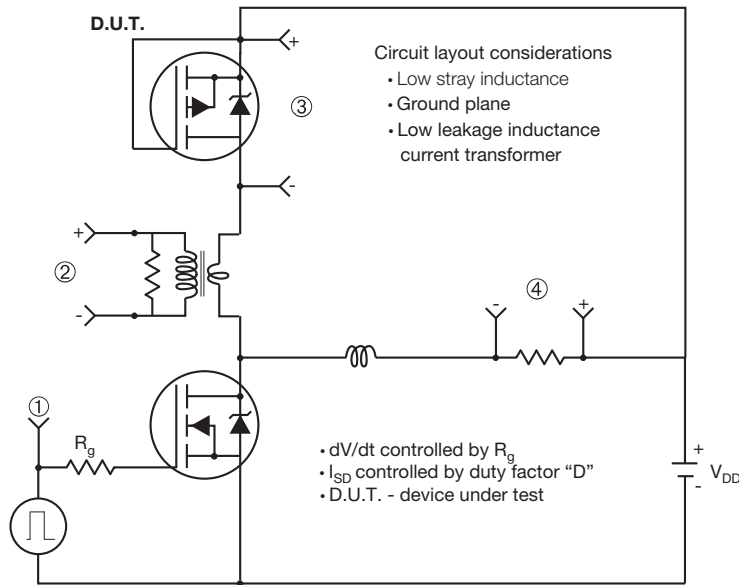
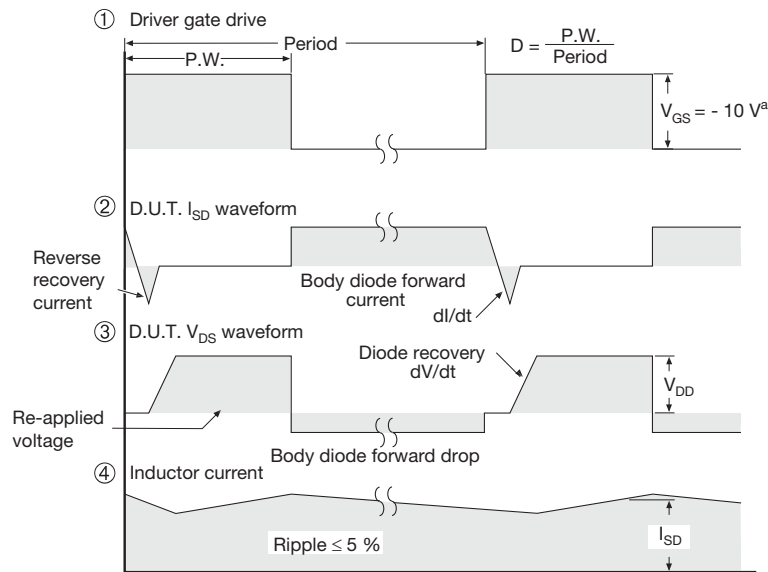


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



Note
• Compliment N-Channel of D.U.T. for driver



Note
a. $V_{GS} = -5\text{ V}$ for logic level and -3 V drive devices

Fig. 14 - For P-Channel

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